

Kinetics of Vapor Phase Infiltration: Fitting Theory to Experimental Measurements

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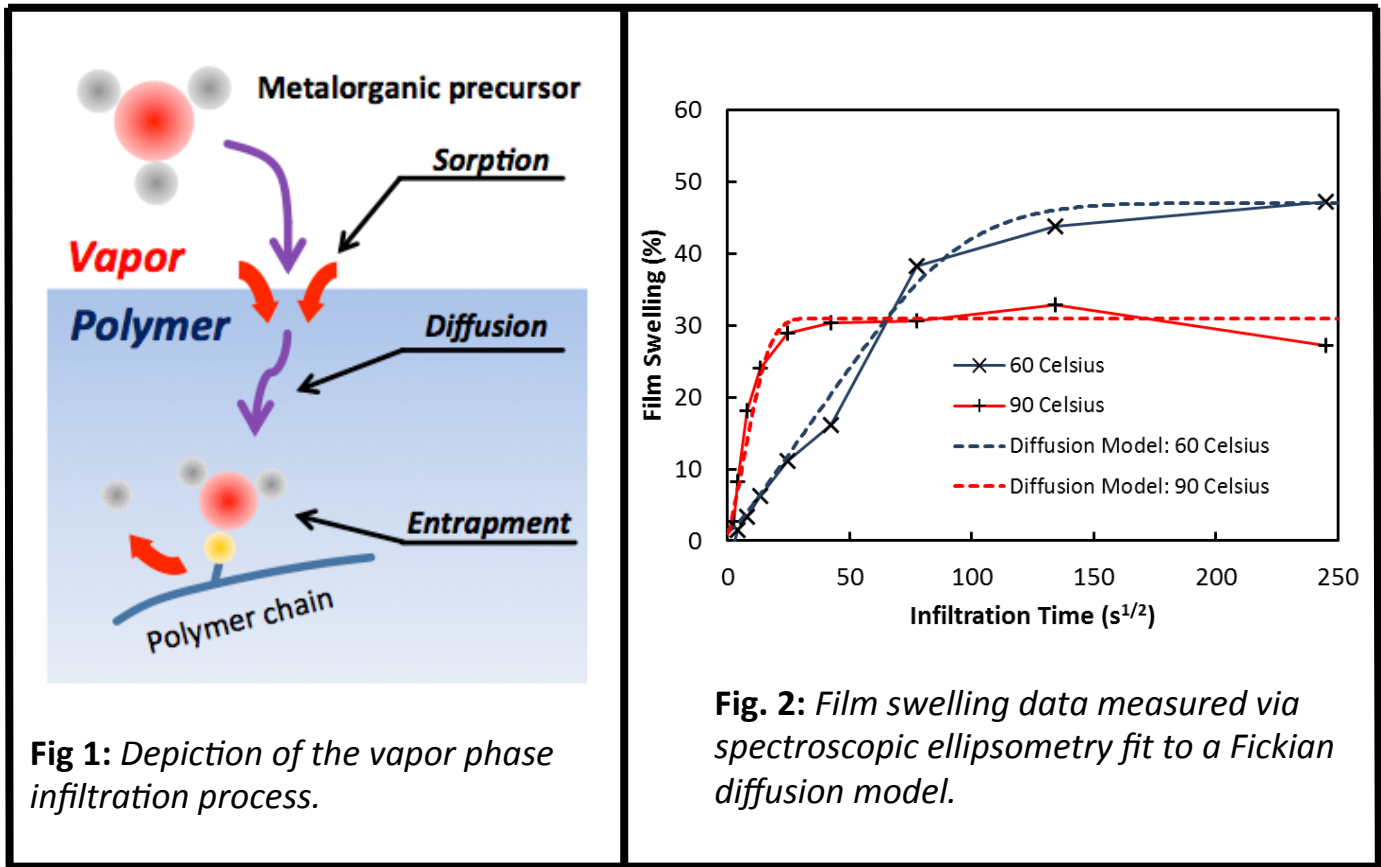


Fig 1: Depiction of the vapor phase infiltration process.

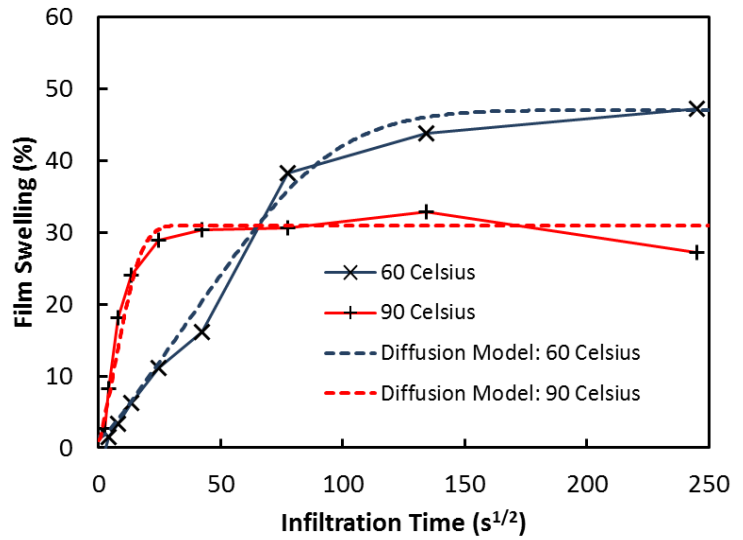


Fig. 2: Film swelling data measured via spectroscopic ellipsometry fit to a Fickian diffusion model.

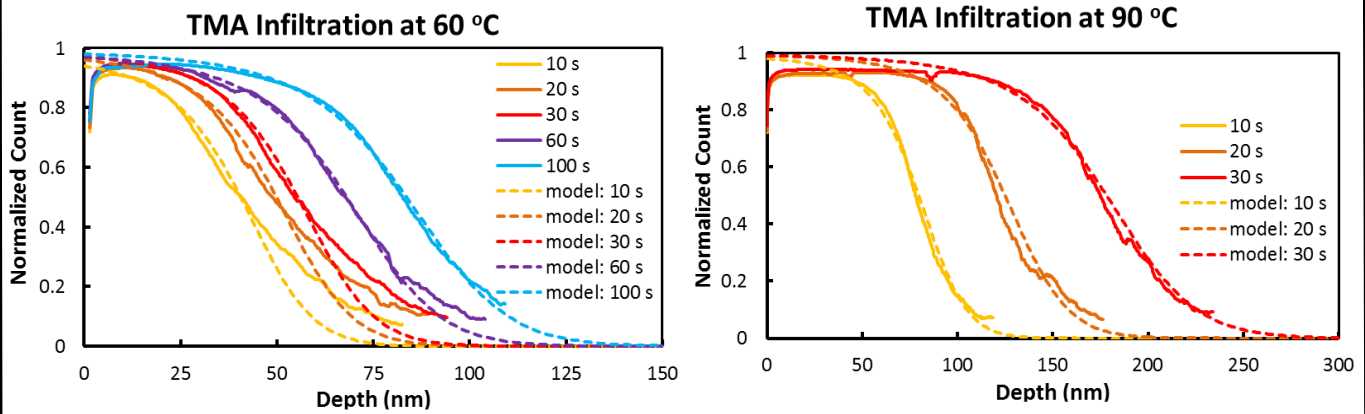


Fig. 3: SIMS compositional depth profiles for TMA VPI PMMA films at varying process conditions fit to a Fickian diffusion model.